

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/735,908	HAN ET AL.	
Examiner	Art Unit	
Tran N. Nguyen	2834	

SEARCHED					
Class	Subclass	Date	Examiner		
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310	156.812	3/3/05	JAN		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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